Application/Control No. O9/932,236 Examiner David L. Hogans Applicant(s)/Patent Under Reexamination YANG, HAINING Art Unit Page 1 of 1

Notice of References Cited

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,211,034	04-2001	Visokay et al.	438/396
	В	US-			430/330
	С	US-			
	D	US-			
	Е	US-			
	F	US-	-		
	G	US-			
	Н	US-			
	-	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
0					,
Р					
Q					
R					
s					
Т					
	O P Q R	Country Code-Number-Kind Code N O P Q R	Country Code-Number-Kind Code MM-YYYY N O P Q R	Country Code-Number-Kind Code MM-YYYY	Country Code-Number-Kind Code MM-YYYY Country Name N — — — O — — — P — — — Q — — — R — — —

NON-PATENT DOCUMENTS

*		Include as any liceble. A Mr. Till S.
├─	 	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Quirk et al., Semiconductor Manufacturing Technology (2001), Prentice Hall, pages 307-308.
	V	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPFP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.